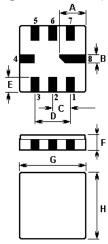


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The ACTQ965/868.35/QCC8C is a two-port, 180° surface-acoustic-wave (SAW) resonator in a surface-mount ceramic QCC8C case. It provides reliable, fundamental-mode, quartz frequency stabilization i.e. in transmitters or local oscillators operating at 868.350 MHz.

# 1.Package Dimension (QCC8C)

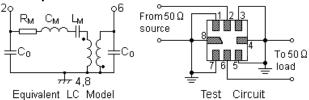


#### 2

Pin	Configuration
2	Input / Output
6	Input / Output
4,8	Case Ground
1,3,5,7	Empty

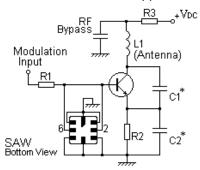
Sign	Data (unit: mm)	Sign	n Data (unit: mm)		
Α	2.08	Е	1.2		
В	0.6	F	1.35		
С	1.27	G	5.0		
D	2.54	Н	5.0		

## 3. Equivalent LC Model and Test Circuit

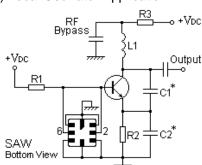


#### 4. Typical Application Circuits

## 1) Low-Power Transmitter Application



## 2) Local Oscillator Application



In keeping with our ongoing policy of product evolvement and improvement, the above specification is subject to change without notice.

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Date : SEPT 04

Issue: 1 C1



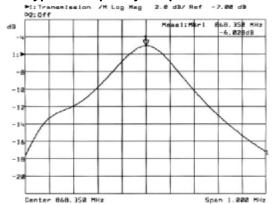
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Issue: 1 C1

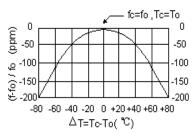
Date: SEPT 04

Email: info@actcrystals.com

### 5. Typical Frequency Response



## **6.Temperature Characteristics**



The curve shown above accounts for resonator contribution only and does not include LC component temperature characteristics.

#### 7.Performance

## 7-1.Maximum Ratings

Rating	Value	Units		
CW RF Power Dissipation	10	dBm		
DC Voltage Between Terminals	±30V	VDC		
Case Temperature	-40 to +85	°C		
Soldering Temperature	+250	°C		

### 7-2. Electronic Characteristics

r-z.Liectionic Orialacteristics									
	Characteristics	Sym	Minimum	Typical	Maximum	Units			
Centre Frequency (+25°C)	Absolute Frequency	f <sub>C</sub>	868.200		868.500	MHz			
	Tolerance from 868.350 MHz	$\Delta f_{C}$		±150		kHz			
Insertion Loss		IL		6.5	8.0	dB			
Quality Factor	Unloaded Q	$Q_{U}$		6,260					
	50 Ω Loaded Q	Q <sub>L</sub>		3,300					
Temperature Stability	Turnover Temperature	T <sub>0</sub>	25		55	°C			
	Turnover Frequency	f <sub>0</sub>		fc		kHz			
	Frequency Temperature Coefficient	FTC		0.03		ppm/°C 2			
Frequency Aging Absolute Value during the First Year		f <sub>A</sub>		≤10		ppm/yr			
DC Insulation Resistance Between Any Two Terminals			1.0			МΩ			
RF Equivalent RLC Model	Motional Resistance	R <sub>M</sub>		111.35	151	Ω			
	Motional Inductance	L <sub>M</sub>		127.8974		μН			
	Motional Capacitance	См		0.2629		fF			
	Shunt Static Capacitance	C <sub>0</sub>	1.20	1.35	1.50	pF			

# i CAUTION: Electrostatic Sensitive Device. Observe precautions for handling!

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- 1. The frequency  $f_C$  is the frequency of minimum IL with the resonator in the specified test fixture in a 50  $\Omega$  test system with VSWR $\leq$ 1.2:1.
- 2. Unless noted otherwise, case temperature  $T_C = +25^{\circ}C \pm 2^{\circ}C$ .
- Frequency aging is the change in f<sub>C</sub> with time and is specified at +65°C or less. Aging may exceed the specification for prolonged temperatures above +65°C. Typically, aging is greatest the first year after manufacture, decreasing in subsequent years.
- 4. Turnover temperature,  $T_0$ , is the temperature of maximum (or turnover) frequency,  $f_0$ . The nominal frequency at any case temperature,  $T_0$ , may be calculated from:  $f = f_0 [1 FTC (T_0 T_0)^2]$ .
- 5. This equivalent RLC model approximates resonator performance near the resonant frequency and is provided for reference only. The capacitance C<sub>0</sub> is the measured static (non-motional) capacitance between input terminal and ground or output terminal and ground. The measurement includes case parasitic capacitance.
- 6. Derived mathematically from one or more of the following directly measured parameters: f<sub>C</sub>, IL, 3 dB bandwidth, f<sub>C</sub> versus T<sub>C</sub>, and C<sub>0</sub>.
- The specifications of this device are based on the test circuit shown above and subject to change or obsolescence without notice.
- 8. Typically, equipment utilizing this device requires emissions testing and government approval, which is the responsibility of the equipment manufacturer.
- 9. Our liability is only assumed for the Surface Acoustic Wave (SAW) component(s) per se, not for applications, processes and circuits implemented within components or assemblies.

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